

Composing graph theory and deep neural networks to evaluate SEU type soft error effects

Balakrishnan, Aneesh; Lange, Thomas; Glorieux, Maximilien; Alexandrescu, Dan; Jenihhin, Maksim 9th Mediterranean Conference on Embedded Computing (MECO'2020), Budva, Montenegro, 8-11 June 2020 2020
<https://doi.org/10.1109/MECO49872.2020.9134279>

Gate-level graph representation learning : a step towards the improved stuck-at faults analysis

Balakrishnan, Aneesh; Alexandrescu, Dan; Jenihhin, Maksim; Lange, Thomas; Glorieux, Maximilien Proceedings of the Twenty Second International Symposium on Quality Electronic Design (ISQED) : Santa Clara, USA, 7-9 April 2021 2021 / p. 24-30
<https://doi.org/10.1109/ISQED51717.2021.9424256>